

March 2013

FQPF27P06 P-Channel QFET® MOSFET -60 V, -17 A, 26 m Ω

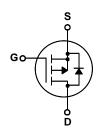
Description

This P-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor[®]'s proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, audio amplifier, DC motor control, and variable switching power applications.

Features

- -17 A, -60 V, $R_{DS(on)}$ =26 m $\Omega(Max.)$ @ V_{GS} =-10 V, I_D =-8.5 A
- Low Gate Charge (Typ. 33 nC)
- Low Crss (Typ. 120 pF)
- 100% Avalanche Tested
- 175°C Maximum Junction Temperature Rating





Absolute Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Parameter		FQPF27P06	Unit
V _{DSS}	Drain-Source Voltage		-60	V
I _D	Drain Current - Continuous (T _C = 25°C) - Continuous (T _C = 100°C)		-17	А
			-12	А
I _{DM}	Drain Current - Pulsed	(Note 1)	-68	А
V _{GSS}	Gate-Source Voltage		± 25	V
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	560	mJ
I _{AR}	Avalanche Current	(Note 1)	-17	А
E _{AR}	Repetitive Avalanche Energy	(Note 1)	4.7	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	-7.0	V/ns
P _D	Power Dissipation (T _C = 25°C)		47	W
	- Derate above 25°C		0.31	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +175	°C
TL	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C
'L			300	

Thermal Characteristics

Symbol	Parameter	Тур	Max	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		3.19	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		62.5	°C/W

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
Off Cha	racteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = -250 \mu\text{A}$	-60			V
ΔBV_{DSS}	Breakdown Voltage Temperature Coefficient	I _D = -250 μA, Referenced to 25°C		-0.06		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = -60 V, V _{GS} = 0 V			-1	μΑ
		V _{DS} = -48 V, T _C = 150°C			-10	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = -25 V, V _{DS} = 0 V			-100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = 25 V, V _{DS} = 0 V			100	nA
On Cha	racteristics					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$	-2.0		-4.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = -10 V, I _D = -8.5 A		0.055	0.07	Ω
9 _{FS}	Forward Transconductance	$V_{DS} = -30 \text{ V}, I_{D} = -8.5 \text{ A}$ (Note 4)		12		S
C _{iss} C _{oss} C _{rss}	Output Capacitance Reverse Transfer Capacitance	$V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz		510 120	660 155	pF pF
C _{rss}	Reverse Transfer Capacitance			120	155	pF
Switchi	ng Characteristics					
t _{d(on)}	Turn-On Delay Time	V _{DD} = -30 V, I _D = -13.5 A,		18	45	ns
t _r	Turn-On Rise Time	$R_G = 25 \Omega$		185	380	ns
t _{d(off)}	Turn-Off Delay Time	_		30	70	ns
t _f	Turn-Off Fall Time	(Note 4, 5)		90	190	ns
Q_g	Total Gate Charge	$V_{DS} = -48 \text{ V}, I_{D} = -27 \text{ A},$		33	43	nC
Q _{gs}	Gate-Source Charge	V _{GS} = -10 V		6.8		nC
Q _{gd}	Gate-Drain Charge	(Note 4, 5)		18		nC
Drain-S	ource Diode Characteristics a	nd Maximum Ratings				
I _S	Maximum Continuous Drain-Source Diode Forward Current				-17	Α
I _{SM}	Maximum Pulsed Drain-Source Diode F	Drain-Source Diode Forward Current			-68	Α
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = -17 A			-4.0	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_{S} = -27 \text{ A},$		105		ns
711	,					

- **Notes:**1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 2.25mH, I_{AS} = -17A, V_{DD} = -25V, R_{G} = 25 Ω , Starting T_{J} = 25°C 3. I_{SD} ≤ -27A, di/dt ≤ 300A/μs, V_{DD} ≤ BV $_{DSS}$, Starting T_{J} = 25°C 4. Pulse Test : Pulse width ≤ 300μs, Duty cycle ≤ 2% 5. Essentially independent of operating temperature

Typical Characteristics

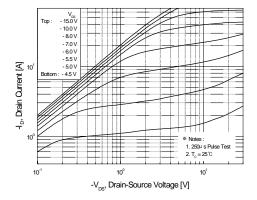


Figure 1. On-Region Characteristics

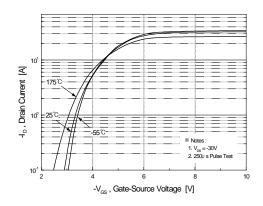


Figure 2. Transfer Characteristics

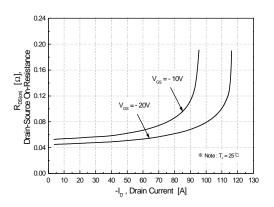


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

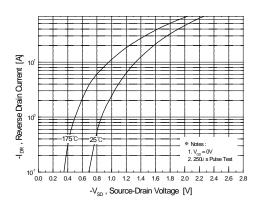


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

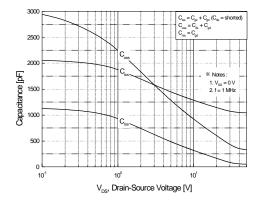


Figure 5. Capacitance Characteristics

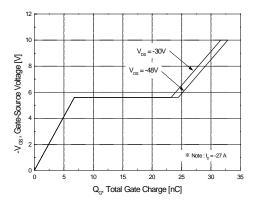
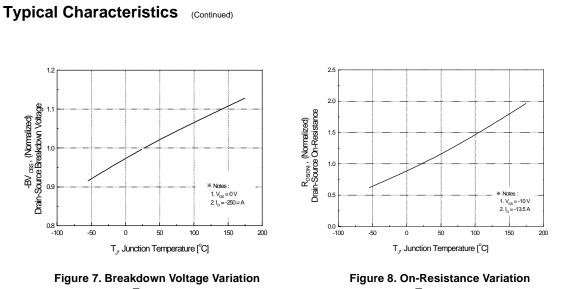
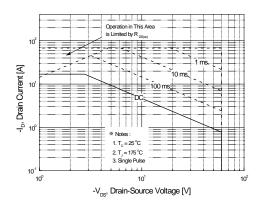


Figure 6. Gate Charge Characteristics



vs. Temperature

vs. Temperature



I., Drain Qurrent [A] $T_{_{\mathbb{C}}}$, Case Temperature [${}^{^{\circ}}\!\mathbb{C}$]

Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

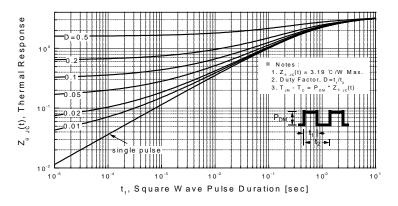
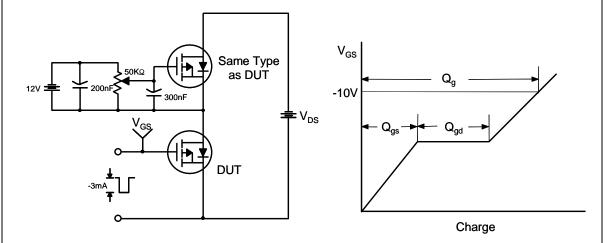
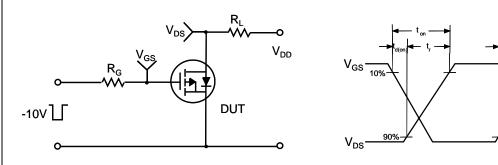


Figure 11. Transient Thermal Response Curve

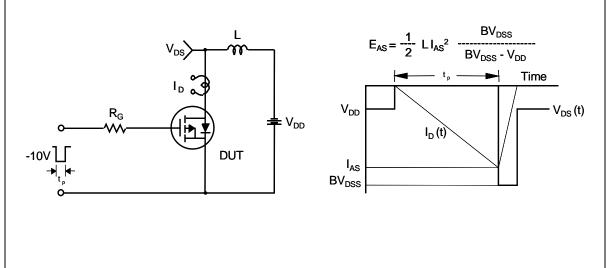
Gate Charge Test Circuit & Waveform



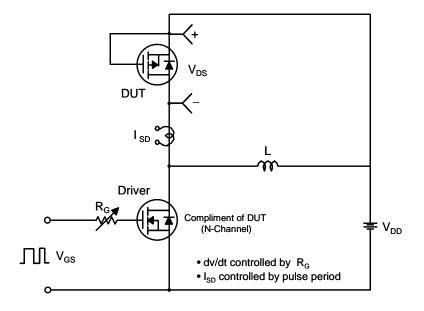
Resistive Switching Test Circuit & Waveforms

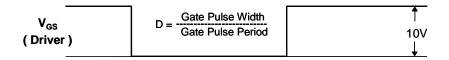


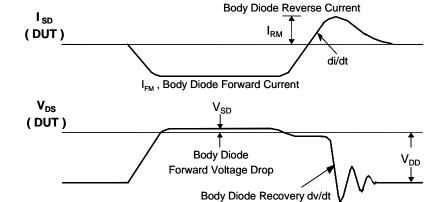
Unclamped Inductive Switching Test Circuit & Waveforms

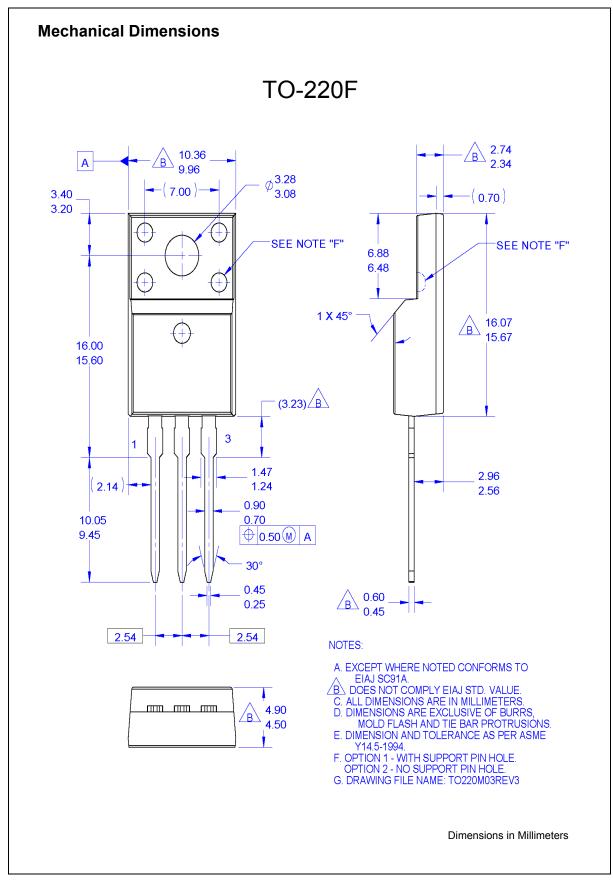


Peak Diode Recovery dv/dt Test Circuit & Waveforms













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